

DESCRIPTION

The MXD20N45 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a wide variety of applications.

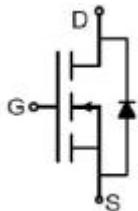
GENERAL FEATURES

- V_{DS}=20V, I_D=85A
 $R_{DS(ON)}(\text{Typ.})=6\text{m}\Omega$ @ V_{GS}=2.5V
 $R_{DS(ON)}(\text{Typ.})=3.9\text{m}\Omega$ @ V_{GS}=4.5V
- High Power and current handing capability
- Lead free product is acquired
- Surface Mount Package

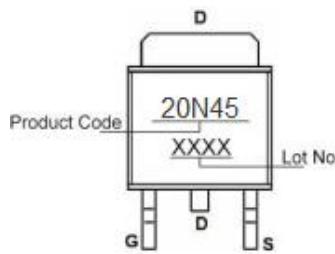
APPLICATION

- Battery Protection
- Load switch
- Power management

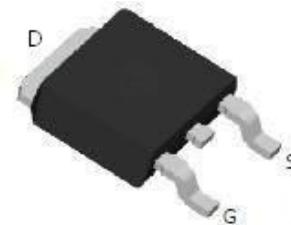
PINOUT



Schematic diagram



Marking and Pin Assignment



TO-252 top view

ORDERING INFORMATION

Device	Storage Temperature	Package	Devices Per Reel
MXD20N45	-55°C to 175°C	TO-252	2500

KEY PERFORMANCE PARAMETERS ($T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage($V_{GS}=0\text{V}$)	V _{DS}	20	V
Gate-Source Voltage($V_{DS}=0\text{V}$)	V _{GS}	± 12	V
Drain Current-Continuous($T_c=25^\circ\text{C}$) ^(Note1)	I _D	85	A
Drain Current-Continuous($T_c=100^\circ\text{C}$)	I _D	59	A
Drain Current-Continuous@Current-Pulsed ^(Note2)	I _{DM(pluse)}	340	A
Maximum Power Dissipation($T_c=25^\circ\text{C}$)	P _D	87	W
Maximum Power Dissipation($T_c=100^\circ\text{C}$)	P _D	43	W
Single Pulse Avalanche Energy ^(Note3)	E _{AS}	340	mJ
Operating Junction and Storage Temperature Range	T _J , T _{STG}	-55 to 175	°C

THERMAL CHARACTERISTIC

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	R _{θJC}	2.2	°C/W

Notes 1.The maximum current rating is package limited.

Notes 2.Repetitive Rating: Pulse width limited by maximum junction temperature

Notes 3.E_{AS} condition: T_J=25°C, V_{DD}=30V, V_G=4.5V, R_G=25Ω,


ELECTRICAL CHARACTERISTICS($T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
On/Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	20	25	-	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}}=20\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
Gate-Body Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm 12\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	0.5	0.7	1.1	V
Drain-Source On-State Resistance	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}}=2.5\text{V}, I_{\text{D}}=15\text{A}$	-	6	9	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_{\text{D}}=20\text{A}, T_j=125^\circ\text{C}$	-	5.4	8	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_{\text{D}}=20\text{A}, T_j=25^\circ\text{C}$	-	3.9	5.5	$\text{m}\Omega$
Forward Transconductance	g_{FS}	$V_{\text{DS}}=5\text{V}, I_{\text{D}}=15\text{A}$	-	40	-	S

Dynamic Characteristics

Input Capacitance	C_{iss}	$V_{\text{DS}}=15\text{V}, V_{\text{GS}}=0\text{V}, F=1.0\text{MHz}$	-	2800	-	pF
Output Capacitance	C_{oss}		-	353	-	pF
Reverse Transfer Capacitance	C_{rss}		-	265	-	pF
Gate resistance	R_g	$V_{\text{DS}}=0\text{V}, V_{\text{GS}}=0\text{V}, F=1.0\text{MHz}$	-	1.1	-	Ω
Total Gate Charge	Q_g	$V_{\text{DS}}=10\text{V}, I_{\text{D}}=12\text{A}, V_{\text{GS}}=4.5\text{V}$	-	32	-	nC
Gate-Source Charge	Q_{gs}		-	3	-	nC
Gate-Drain Charge	Q_{gd}		-	11	-	nC

Switching Characteristics

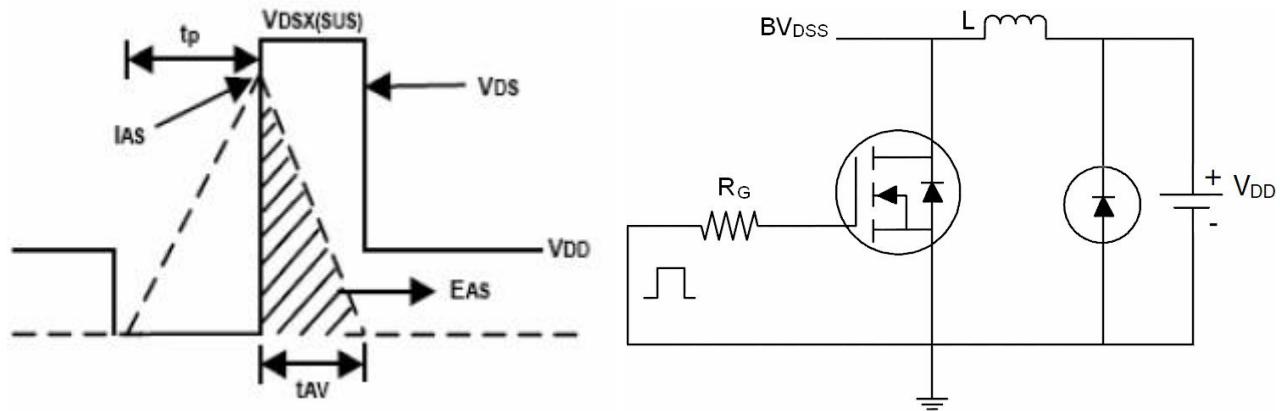
Turn-on Delay Time	$t_{\text{d(on)}}$	$V_{\text{DS}}=15\text{V}, R_L=0.75\Omega$ $V_{\text{GS}}=4.5\text{V}, R_{\text{GEN}}=3\Omega$	-	17	-	nS
Turn-on Rise Time	t_r		-	49	-	nS
Turn-Off Delay Time	$t_{\text{d(off)}}$		-	74	-	nS
Turn-Off Fall Time	t_f		-	26	-	nS

Source-Drain Diode Characteristics

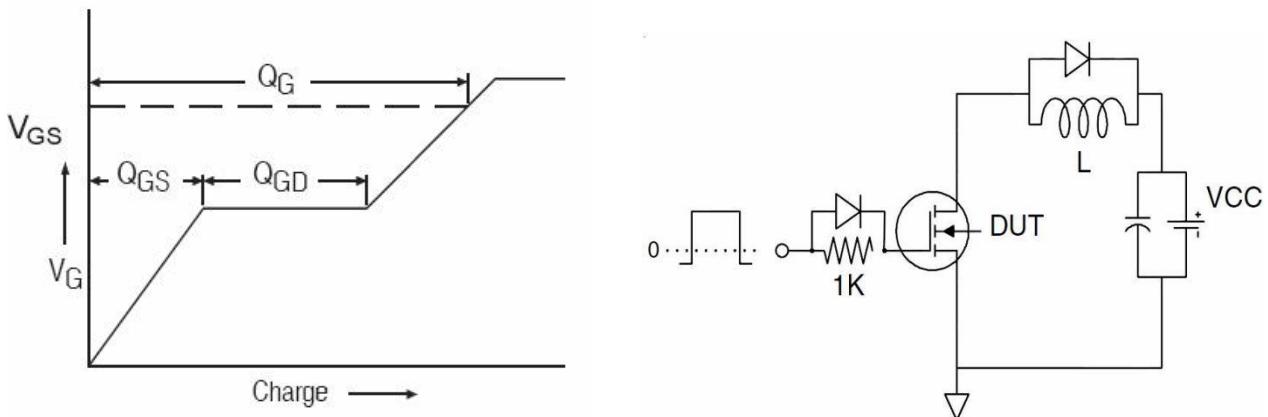
Source-Drain Current(Body Diode)	I_{SD}	$I_F=20\text{A}, dI/dt=100\text{A}/\mu\text{s}$	-	-	85	A	
Forward On Voltage	V_{SD}		$V_{\text{GS}}=0\text{V}, I_{\text{SD}}=20\text{A}$	-	-	1.2	V
Reverse Recovery Time	t_{rr}		-	23	-	nS	
Reverse Recovery Charge	Q_{rr}		-	10	-	nC	

TEST CIRCUIT

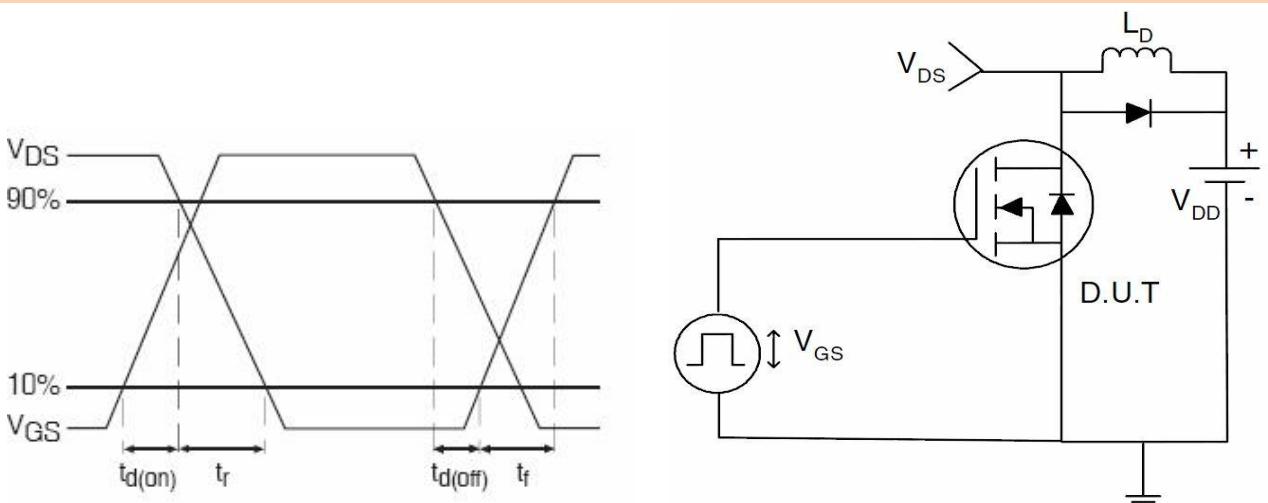
1) EAS Test Circuits



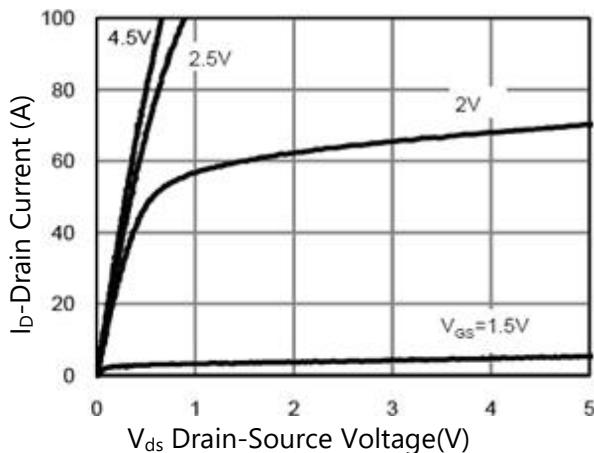
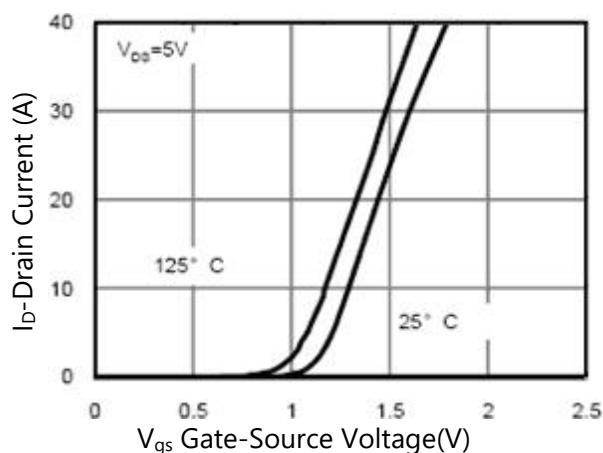
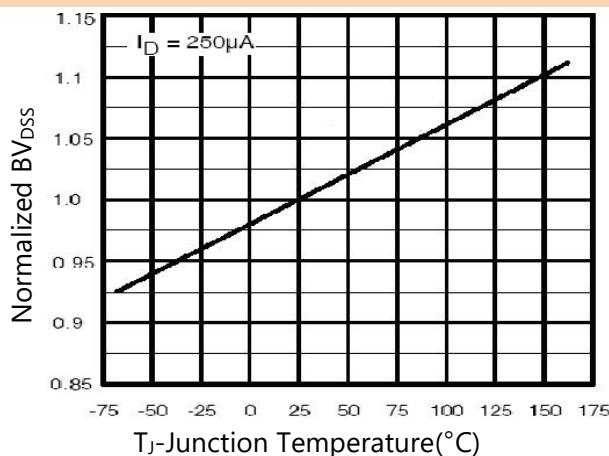
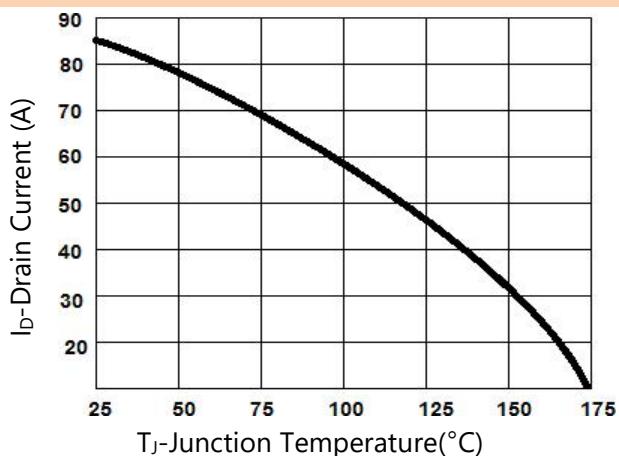
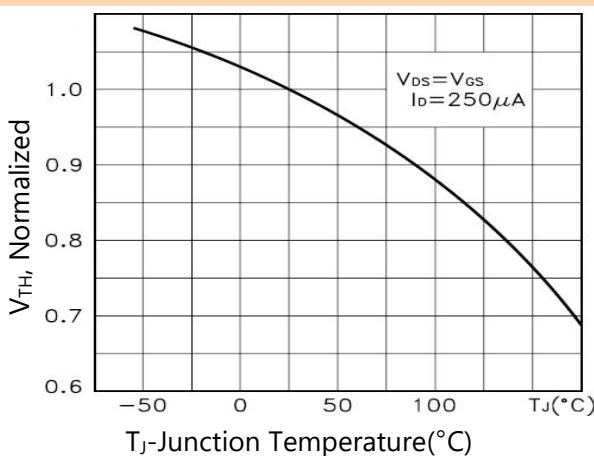
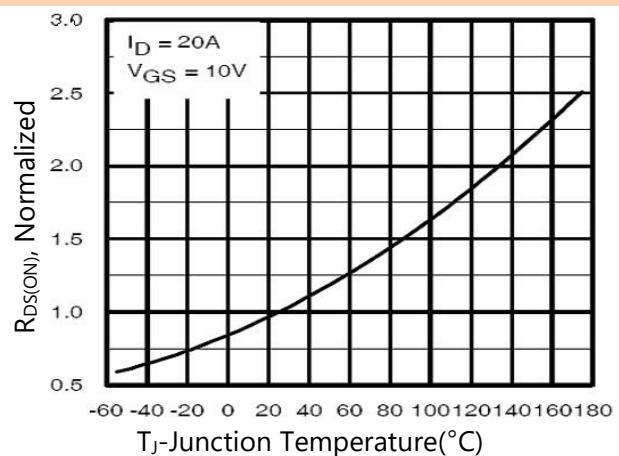
2) Gate Charge Test Circuit



3) Switch Time Test Circuit



TYPICAL PERFORMANCE CHARACTERISTICS

Figure1. Output Characteristics

Figure2. Transfer Characteristics

Figure3. BV_{DSS} vs Junction Temperature

Figure4. Drain Current

Figure5. $V_{GS(th)}$ vs Junction Temperature

Figure6. $R_{DS(ON)}$ vs Junction Temperature


TYPICAL PERFORMANCE CHARACTERISTICS

Figure7. Gate Charge Waveforms

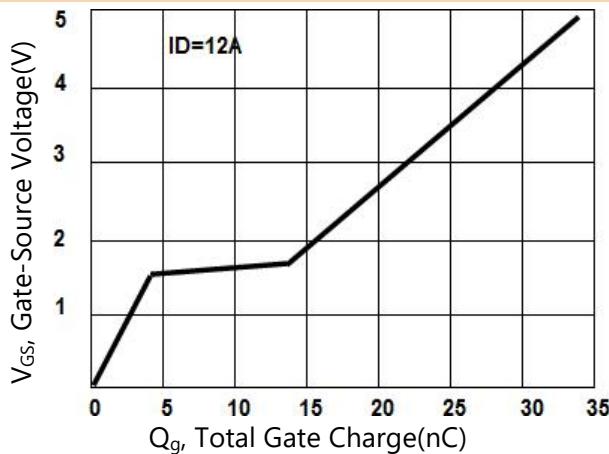


Figure8. Capacitance

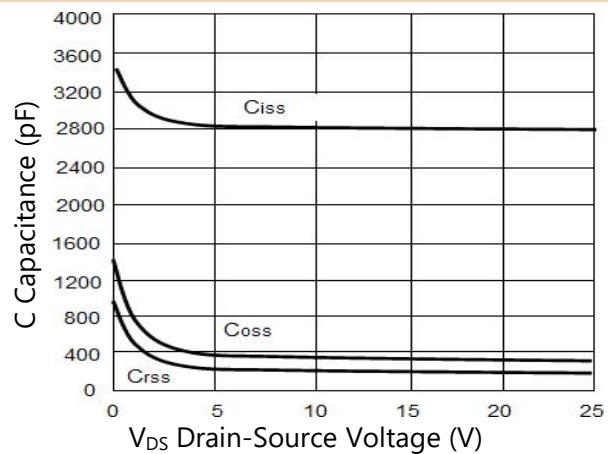


Figure9. Body Diode Forward

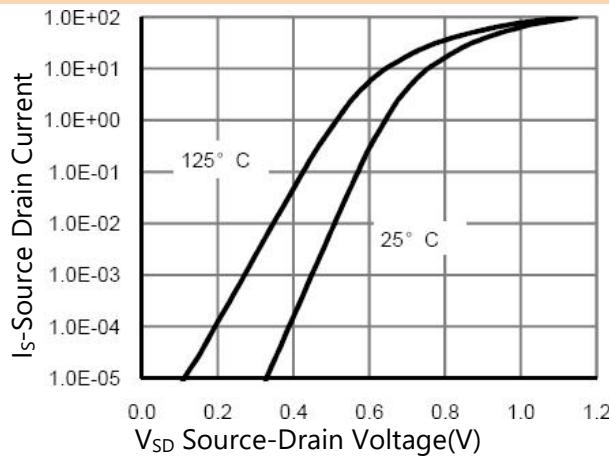


Figure10. Maximum Safe Operating Area

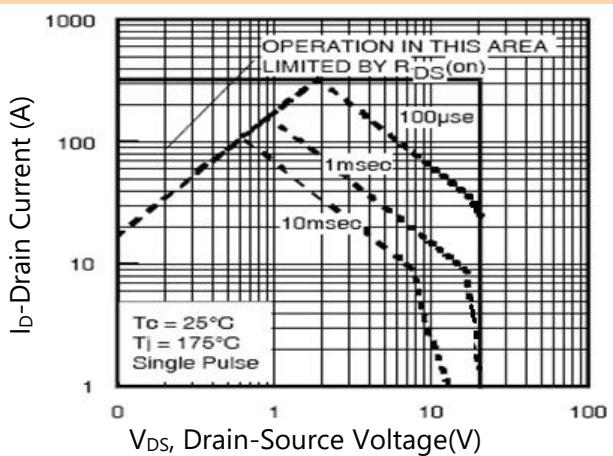
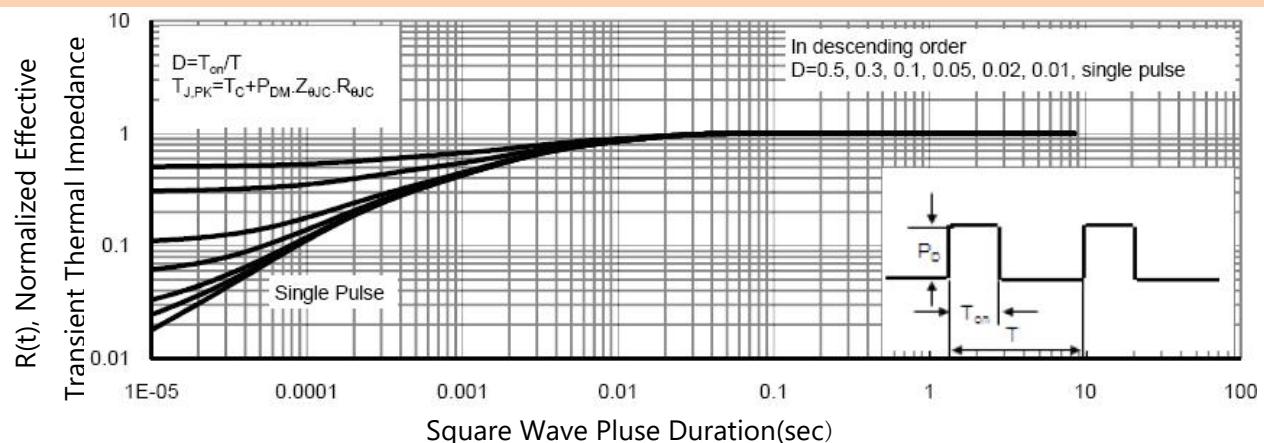
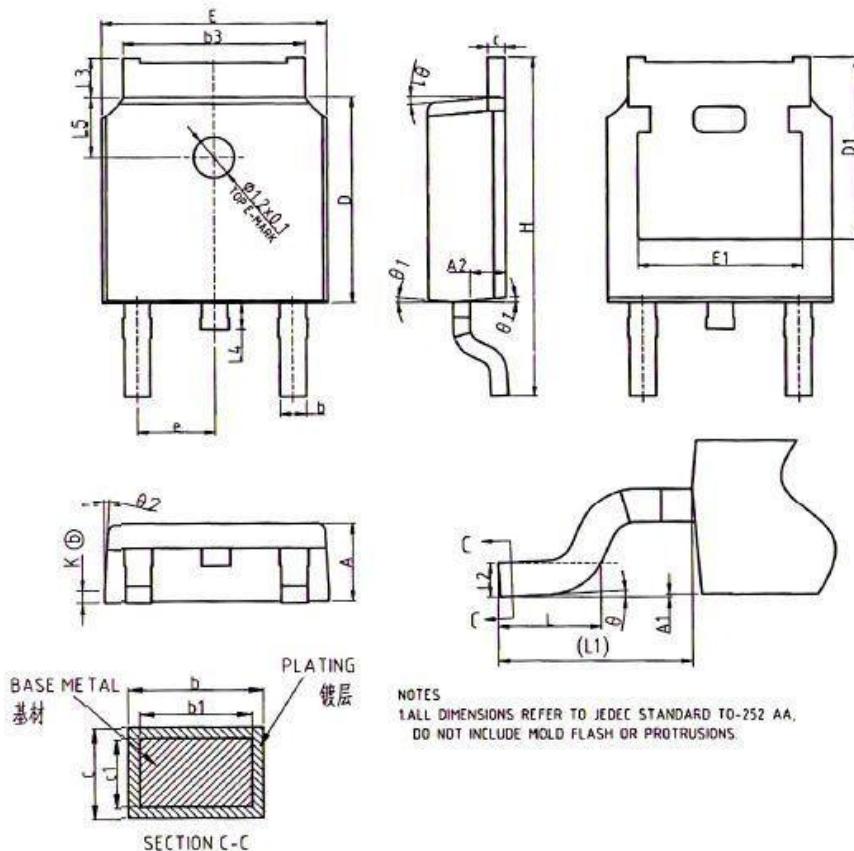


Figure11. Normalized Maximum Transient Thermal Impedance



PACKAGE INFORMATION

TO-252


SYMBOL	COMMON DIMENSIONS IN MILLIMETERS			SYMBOL	COMMON DIMENSIONS IN MILLIMETERS		
	MIN	NOM	MAX		MIN	NOM	MAX
A	2.20	2.30	2.38	H	9.90	10.10	10.30
A1	0.00	-	0.10	L	1.40	1.50	1.70
A2	0.97	1.07	1.17	L1	2.90REF		
b	0.72	0.78	0.85	L2	0.51BSC		
b1	0.71	0.76	0.81	L3	0.90	-	1.25
b3	5.23	5.33	5.46	L4	0.60	0.80	1.00
c	0.47	0.53	0.58	L5	1.70	1.80	1.90
c1	0.46	0.51	0.56	θ	0°	-	8°
D	6.00	6.10	6.20	θ1	5°	7°	9°
D1	5.30REF			θ2	5°	7°	9°
E	6.50	6.60	6.70	K	0.40REF		
E1	4.70	4.83	4.92				
e	2.286BSC						